Integrated Molecular Beam Epitaxy System Model IMBE300

Epitaxial Growth Process with integrated monitoring, 2-D crystallography. composition and electronics band analysis in one UHV chamber.



TECHNIQUES:

- LEED (Low Energy Electron Diffraction)
- AES (Auger Electron Spectroscopy)
- 7 Deposition Sources

- XPS (X-Ray Photoelectron Spectroscopy)
- RHEED (Reflection High Energy Electron Diffraction)
- TDS (Thermal Desorption Mass Spectroscopy)



- No need to transfer to another UHV chamber for analysis after film growth
 - Short switching time between deposition and surface science analysis

- Load-lock with transfer arm and sample storage

- Sample transfer compatibility with other systems: SPM and SEM



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